## Application/Control No. Applicant(s)/Patent Under Reexamination 10/760,281 CHEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Adam C. Rehm 2875 **U.S. PATENT DOCUMENTS** Date **Document Number** Classification Name Country Code-Number-Kind Code MM-YYYY 362/555 Α US-2005/0128767 06-2005 Wang et al. 362/293 03-2004 В US-2004/0052076 Mueller et al. US-С D US-US-Ε F US-G US-Н USi US-US-Κ US-US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Classification Name Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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